Presents a Seminar

On

Introduction of XPS and EDS/WDS Microanalysis in the field of electron microscope

By

Dr. Michael Mannsberger (Area manager surface analysis)
Dr. Hans Dijkstra (Application specialist microanalysis)

Thermo Fisher Scientific, Vienna, Austria, EU

Abstract

Thermo Fisher Scientific provides a versatile characterization platform by offering XPS analysis for chemical composition of thin film materials. The focus of this talk will be how quantitative compositional phase mapping can be accomplished in the field of Electron Microscopy by this state of art technique. Furthermore, introduction and capabilities of EDS/WDS detector will also be discussed in detail. Finally, applications of this state of art technology in variety of research areas and materials will be presented.

All are cordially welcome